

GE 159 Plastics Avenue Pittsfield, MA 01201 USA

September 14, 2007

Dean Tagliaferro EPA Project Coordinator c/o Weston Solutions, Inc. 10 Lyman Street Pittsfield, MA 01201

Re: Summary of 2007 Sediment Sampling Activities and Analytical Results Upper ¹/₂-Mile Reach of the Housatonic River (GECD800) GE-Pittsfield/Housatonic River Site

Dear Mr. Tagliaferro:

As required by the *Removal Action Work Plan for the Upper ½-Mile Reach of Housatonic River* (Work Plan; BBL, 1999), which is Appendix F to the Consent Decree (CD) for the GE-Pittsfield/Housatonic River Site, the General Electric Company (GE) has collected and analyzed samples of (1) the sediments that have deposited on top of the cap installed as part of the remediation of the Upper ½-Mile Reach of the Housatonic River (½-Mile) in Pittsfield, Massachusetts, and (2) isolation layer materials within that cap. For both the deposited sediments (referred to as "restored sediments" in the Work Plan) and the isolation layer materials, these sampling and analytical activities were performed to satisfy the Work Plan's "5-Year" monitoring requirements. This letter summarizes the sampling activities performed and presents a summary and discussion of the associated analytical results.

Deposited Sediment Sampling and Analysis

Sampling Activities

GE collected post-remediation sediment samples at 39 locations within the ¹/₂-Mile on May 24-25, 2007 during low flow conditions. The locations sampled are depicted on Figure 1. This sampling was performed in satisfaction of the monitoring requirements set forth in Section 11.5.4 of the Work Plan and in accordance with the procedures described in GE's *Model Input Addendum* to the Corrective Measures Study Proposal for the Housatonic Rest of River (MIA;

QEA/ARCADIS BBL, 2007), as modified by the Environmental Protection Agency's (EPA's) May 24, 2007 conditional approval letter for the MIA. A summary of the sampling activities is provided below.

1. Sediment samples were collected from the 39 locations (shown on Figure 1) using Lexan[®] core tubes.

2. At each location, the approximate extent of sediment deposition was probed and the resultant location-specific thickness was recorded. To the extent practicable, following probing, sediment samples were collected such that the full sediment inventory deposited on top of the armor stone (i.e., those materials deposited since the completion of restoration activities) was collected at each sampling location. As a result, the approximate sediment thickness and sediment recovery length measured and recorded at each location represent the approximate net deposition on a location-specific basis and thus differ from location to location. To account for such variability, based on discussions between GE and EPA, samples were collected from the approximate 0- to 6-inch interval (or less where recovery was less than 6 inches) and from the 6- to X-inch interval, where X represents the maximum recovery depth of sediments from the depositional layer on top of the underlying armor stone. GE collected 39 samples (plus two duplicates) of the surface sediments (top 6 inches or less) and 12 samples (plus one duplicate) of subsurface sediments (deeper than 6 inches), for a total of 51 sediment samples (plus three duplicates).

3. Collected cores were processed in the field and samples from each core were submitted for analysis in accordance with GE's current *Field Sampling Plan/Quality Assurance Project Plan* (FSP/QAPP; ARCADIS BBL, 2007). For all 51 samples discussed above, laboratory analyses for polychlorinated biphenyls (PCBs) and total organic carbon (TOC) were performed by Northeast Analytical, Inc. (NEA) in Schenectady, New York. Portions of 23 of these samples were also submitted to Geotechnics, Inc. in Pittsburgh,

Pennsylvania, for grain size analysis. At the time of sample processing, Weston Solutions, Inc., on EPA's behalf, collected 12 split samples (plus one duplicate) for analysis.

Results

As discussed above, sediment recovery lengths and probing thicknesses were recorded at each location. Sediment thicknesses, as estimated in the field, ranged from 2 to 30 inches, with an average thickness of 7.28 inches and a median of 6.0 inches. Similarly, sediment core recovery lengths ranged from 2 to 25 inches, with an average recovery of 6.7 inches and a median of 6.0 inches. Location-specific sediment probing thicknesses and maximum recovery lengths are summarized in Table 1. Grain size analysis results indicate that the majority of the collected materials were within the fine- to coarse-sand size range, with a less frequent occurrence of gravel and with a small percentage of silt (typically less than 2% by weight). Grain size analytical data are also summarized in Table 1. Field observations at the time of sample collection noted a petroleum odor at five locations; four of these locations were located at the upstream end of the ¹/₂-Mile and the fifth (RS-C17) was located at the approximate midpoint of the ¹/₂-Mile (see Table 1 and Figure 1).

Analytical results for PCBs and TOC in the sediment samples collected by GE are presented in Table 2. PCB concentrations reported for GE's samples ranged from non-detect to 10.6 milligrams per kilogram (mg/kg) (sample location RS-C17, 6- to 25-inch depth interval), with an overall average of 0.6 mg/kg (duplicate samples have been averaged for this report). In calculating average concentrations for this report, one-half the detection limit was used for any sample in which the concentration was reported as non-detect. Of the 51 sediment samples (after averaging the duplicate results), 45 samples (88%) showed PCB concentrations less than 1.0 mg/kg, 44 (86%) less than 0.5 mg/kg, and 12 (24%) less than 0.1 mg/kg. Three samples had no detectable PCB concentrations. TOC concentrations ranged from 0.13% to 2.3% (location RS-C29, 6- to 8-inch depth interval), with an average of approximately 0.4%.

PCB concentrations were generally lower in the surface samples (i.e., 0- to 6-inch or less), with arithmetic average concentrations in the surface and subsurface samples of 0.24 mg/kg and 1.8 mg/kg, respectively. The subsurface average is skewed, however, by the highest PCB concentrations. Exclusion of the highest concentration (10.4 mg/kg) reduces the subsurface average by approximately half, from 1.8 mg/kg to 0.96 mg/kg. TOC concentrations were also generally lower in surface samples, with arithmetic average concentrations of 0.34% and 0.57% in the surface and subsurface samples, respectively. Additionally, of the six samples with PCB analytical results greater than 1.0 mg/kg, four were collected from the subsurface, and PCB analytical results for 10 of the 12 locations from which subsurface samples.

For the split samples collected by Weston for EPA, Table 3 presents the PCB analytical results both for the co-located GE samples and for the EPA split samples. Analytical data from the EPA split samples ranged from 0.040 mg/kg to 3.25 mg/kg (average of two duplicate samples), with an overall average of 0.49 mg/kg (compared to an overall average of 0.60 mg/kg for the GE samples). In general, the results of the split samples were consistent with the results of the GE samples; the highest EPA result corresponded to the highest GE result, and the majority of the samples showed low PCB levels with similar variabilities. Consistent with the GE samples, PCB concentrations were higher in the subsurface samples.

Isolation Layer Sampling and Analysis

Sampling Activities

Section 11.5.1 of the Work Plan requires that sampling of the isolation layer materials within the ¹/₂-Mile cap be conducted at six locations immediately after placement of the cap, one year after cap placement, and at the end of the initial five-year period after cap placement. EPA subsequently selected two additional locations for such sampling. The immediate post-placement sampling and one-year post-placement sampling of the isolation layer materials were

conducted on staggered occasions during 2000, 2001, 2002, and 2003, depending on the timing of cap placement at those locations. The results of these sampling events were presented in GE's Annual Monitoring Reports for the ¹/₂-Mile for 2001 (dated March 2002), 2002 (dated December 2002), and 2003 (dated February 2004).

With EPA's concurrence, the timing for the 5-Year isolation layer monitoring event was consolidated for all 8 locations to a single event in 2007. GE collected isolation layer material samples at these 8 locations on August 10, 2007. A summary of these sampling activities is provided below.

1. At each of the 8 locations (shown on Figure 1), the overlying armor stone and any sediment deposited within or on top of the armor layer were, to the extent practicable, removed by hand to expose the geogrid and geotextile layers that had been placed on top of the isolation layer. Once exposed, the geogrid and geotextile layers were temporarily cut back to allow access to the underlying isolation layer. Two cores of the isolation layer material were then collected at each sampling location, using Lexan[®] core tubes.

2. Collected cores were processed in the field and samples from each core were submitted for analysis in accordance with GE's current FSP/QAPP (ARCADIS BBL, 2007). Consistent with the requirements of the Work Plan, one core from each location was sectioned into 2-inch increments, providing core segments from the 2- to 4-inch, 4- to 6-inch, and 6- to 8-inch intervals proceeding upward from the bottom geotextile layer (i.e., the 2- to 4-inch segment is the deepest). These core segment samples were sent to NEA for PCB and TOC analyses. The second core from each location remained intact, and a composite sample representing the entire length of that core was also sent to NEA for TOC analysis.

Results

Analytical results for PCBs and TOC in the isolation layer material samples are presented in Table 4. For comparison, the related results from the previous isolation layer sampling events, as well as the post-excavation surface sediment sample results for each location, are also included in Table 4. PCB concentrations reported for the most recent sampling event range from non-detect to 0.21 mg/kg (sample location CAP-MON-6, 2- to 4-inch depth interval). Overall, PCB detections were relatively infrequent and low; only 6 of the 24 total samples (25%) had detectable PCB concentrations, with 3 of the reportable concentrations below 0.10 mg/kg (i.e., approaching reportable detection limits), and the remaining 3 below 0.25 mg/kg. Four of these 6 samples were collected from the 2- to 4-inch depth interval, with one each from the 4- to 6-inch and 6- to 8-inch depth intervals. TOC concentrations ranged from 0.21% to 1.8%, with an average of approximately 0.98%. TOC analytical data for the full-depth cores ranged from 0.15% to 1.7%, with an average of 0.72%.

Discussion

Deposited Sediment

The PCB data from the deposited sediments collected from the ½-Mile indicate the presence of low levels of PCBs in the materials that have been deposited on top of the armor stone since completion of the ½-Mile sediment remediation and restoration activities. The Work Plan provides (pp. 2-3 & 11-6) that if such sampling indicates the deposition of PCBs on the surface of these sediments, GE will "evaluate, to the extent feasible, the source of such PCBs." It then states that, if that evaluation indicates that the surface PCBs "are attributable to sources other than those that have been or are being addressed at the GE-Pittsfield/Housatonic River Site" (as defined in the CD), then GE will evaluate potential source control measures for such sources. However, if those conditions are not met (i.e., if GE cannot attribute the surface PCBs to sources other than those that have been or are being addressed under the CD), then "no further response actions shall be required to address such PCBs deposited on the surface" (unless necessary to address bank erosion or unless the reopener conditions in the CD are met).

Given the sporadic distribution and very low concentrations of PCBs observed in the isolation layer materials (Table 4), it appears evident that upward migration of PCBs is not a potential source of the PCBs in the deposited sediments. Beyond that, based on review of the PCB data from the deposited sediments and from potential source areas, GE has determined that it is not feasible to make a definitive evaluation of the sources of the PCBs in these deposited sediments. GE's recent *Supplement to Model Input Addendum, Housatonic Rest of River CMS Proposal* (MIA Supplement; QEA/ARCADIS BBL, 2007) identifies a number of likely sources of PCBs to the ¹/₂-Mile. Most of these are located at the GE-Pittsfield/Housatonic River Site and have been or will be remediated under the CD. Such areas include the banks of the ¹/₂-Mile, portions of the GE Plant Area, Unkamet Brook, and certain Former Oxbow Areas. While other sources may also exist, the extent (if any) to which they may have contributed to the surface sediment PCBs in the ¹/₂-Mile cannot be determined at this time.

In short, it cannot be concluded that the PCBs in the ¹/₂-Mile surface sediments are attributable to sources other than those that have been or are being addressed by GE at the Pittsfield/Housatonic River Site (as defined in the CD). In these circumstances, in accordance with the Work Plan, GE believes that no further response actions are required at this time to address the PCBs in the surface of the ¹/₂-Mile sediments.

Isolation Layer

The Work Plan requires the periodic sampling of the isolation layer to assess the effectiveness of the isolation layer in limiting PCB migration from the underlying sediments. It provides that if this sampling indicates that "the isolation layer is not performing in general accordance with the predictions on which the isolation layer design was based in terms of controlling PCB migration from the underlying sediments into the surface water of the River," GE will evaluate and propose to EPA appropriate corrective actions (p. 2-2; see also p. 11-5). However, if

such sampling indicates that "the isolation layer is performing as generally predicted in terms of controlling PCB migration from the underlying sediments, no further response actions shall be required for the isolation layer" (unless necessary to address deficiencies in the armor stone or to address bank erosion or unless the reopener conditions in the CD are met) (p. 2-2). Further, the Work Plan provides that at the end of the initial five-year period, GE will propose an appropriate long-term monitoring frequency for the isolation layer (p. 11-5).

The analytical data from the recent 5-Year sampling event show no detected PCBs at 3 sampling locations, and the results from the other locations show sporadic and low-level detections in different depth increments. While several of the cores had detectable concentrations of PCBs in the lowest core increment (i.e., 2-4 inches), there are neither sufficient data nor has enough time passed to determine whether the PCBs detected in those samples originated from the underlying sediments or from other sources. First, the data show no consistent pattern of PCB detections at the eight isolation layer sample locations that would be indicative of transport from the underlying sediments. Further complicating any interpretation of the data, 2 of the 3 sample depth increments (and locations) that showed detected PCBs in the 1-Year sampling event did not show detected PCBs in the 5-Year event. Moreover, there are other potential explanations for the detected PCBs. For example, the isolation layer core collection methods and the presence of an overlying layer of deposited sediments that contain PCBs could potentially lead to limited mixing of the deposited sediments with the isolation layer material at some locations, which could explain the low concentrations and frequency of PCBs detected in the isolation layer.

Overall, the available isolation layer sampling data do not show a consistent pattern indicative of PCB transport from the underlying sediments and do not allow any definitive conclusions regarding the performance of the isolation layer relative to the long-term predictions on which the isolation layer design was based. It is simply too early to make any such conclusions.

However, the data do indicate that, at the present time, the isolation layer is preventing the migration of PCBs from the underlying sediments to the surface of the isolation layer.

In these circumstances, GE does not believe that any corrective action is necessary or required at this time to address the isolation layer. Rather, GE proposes to continue sampling the isolation layer materials coincident with the deposited sediment sampling program schedule. Specifically, GE proposes the collection and analysis of an additional round of isolation layer samples at the same general time as the "10-Year" deposited sediments sampling event (currently anticipated for performance in 2012). Based on review of those results, GE will further evaluate the effectiveness of the isolation layer. In addition, at that time, GE will evaluate the scope and frequency of further long-term monitoring of the isolation layer, and will make a proposal to EPA regarding such further monitoring.

Please contact me with questions or to discuss the information presented herein.

Sincerely,

Audu T. Lilh

Andrew T. Silfer, P.E. GE Project Coordinator

ATS/dmn

Attachments

cc: Susan Svirsky, EPA Holly Inglis, EPA Tim Conway, EPA Rose Howell, EPA K.C. Mitkevicius, USACE Ray Goff, USACE Linda Palmieri, Weston Susan Steenstrup, MDEP

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Jane Rothchild, MDEP Anna Symington, MDEP Dale Young, MA EOEA Nancy E. Harper, MA AG Mayor James Ruberto, City of Pittsfield Michael Carroll, GE Rod McLaren, GE James Bieke, Goodwin Procter Samuel Gutter, Sidley Austin Stu Messur, ARCADIS BBL Mark Gravelding, ARCADIS BBL Todd Cridge, ARCADIS BBL

Public Information Repositories GE Internal Repositories

TABLE 1 SUMMARY OF DEPOSITED SEDIMENT GRAIN SIZE DISTRIBUTION ANALYTICAL DATA

UPPER 1/2 MILE REACH OF THE HOUSATONIC RIVER GENERAL ELECTRIC COMPANY - PITTSFIELD, MASSACHUSETTS (Grain size distribution data presented in % passing)

									SI	EVE OPE	NING (mi	m)				
Sample Location	Date Collected	Sediment Probing Depth (inches)	Sediment Recovery Depth (Inches)	Sample Increment (inches)	37.5	25	19	12.5	9.5	4.75	2	0.85	0.425	0.25	0.106	0.075
RS-C1	05/25/07	3	3							-	-					
RS-C4*	5/25/2007	7	7	0-7	100	100	100	89.87	84.39	68.45	48.04	32.32	13.16	4.26	1.55	1.12
RS-C7*	05/25/07	5	5							-	-					
RS-C10	5/25/2007	3	3	0-3	100	97.02	89.49	81.29	73.68	58.41	41.53	23.50	10.99	5.56	1.93	1.27
RS-C14	5/25/2007	6	6	0-6	100	100	100	98.07	95.42	88.19	74.60	55.26	26.70	6.87	1.51	0.98
DS C17 *	E/2E/2007	20	25	0-6	100	100	100	99.73	98.91	96.42	85.14	59.77	34.84	15.91	2.95	1.61
K3-C17	5/25/2007	30	23	6-25	100	100	100	99.43	99.13	97.12	94.45	91.66	85.74	68.51	16.80	9.69
RS-C26	5/24/2007	8	6	0-6	100	100	100	97.64	95.58	87.76	75.85	56.25	34.75	14.90	4.78	3.60
RS-C29	5/24/2007	9	8	0-6	100	100	100	99.90	99.80	96.12	71.54	36.06	8.89	2.60	0.65	0.46
RS-C31	5/24/2007	6	6	0-6	100	100	100	99.58	99.29	96.24	74.91	37.97	9.63	2.05	0.55	0.44
RS-C34	5/24/2007	6	6	0-6	100	100	100	99.43	98.96	94.58	73.06	49.69	26.07	11.68	2.40	1.41
RS-C37	05/24/07	9	8							-	-					
RS-N2*	05/25/07	3	3			r			0	-	-		0		n	
RS-N5	5/25/2007	6	6	0-6	100	100	100	99.64	97.37	91.67	80.44	59.84	28.61	7.61	1.67	1.17
RS-N8	05/25/07	2	2			r				-	-					
RS-N11	5/25/2007	11	10	0-6	100	100	100	99.37	97.65	87.74	65.12	42.16	21.80	6.84	2.17	1.71
			-	6-10	100	92.99	92.08	91.58	89.10	77.80	58.48	39.18	21.19	7.29	2.18	1.64
RS-N12	5/25/2007	6	5	0-5	100	100	100	99.10	95.43	84.35	57.75	29.60	11.32	4.92	1.34	0.85
RS-N15	05/25/07	11	9							-	-					
RS-N18	05/24/07	14	14								-					
RS-N27	5/24/2007	7	6	0-6	100	100	100	100	99.83	91.87	49.39	22.94	10.70	4.89	1.43	0.96
RS-N30	05/24/07	4	4		100	400	400	100	100	-	-	55.40	0.00	0.04	0.00	
RS-N32	5/24/2007	9	9	0-6	100	100	100	100	100	99.95	97.43	55.42	2.89	0.84	0.29	0.20
DO NOE	05/04/07	0	0	6-9	100	100	100	100	99.93	97.06	89.15	45.83	7.11	3.92	1.14	0.73
RS-N35	05/24/07	9	8		400	400	07.04	05.74	70.74	-	-	40.00	4.04	0.40	0.00	0.04
RS-53	5/25/2007	6	6	0-6	100	100	97.34	85.74	79.71	57.47	29.40	10.89	4.04	2.16	0.82	0.61
R3-30	05/25/07	3	3								-					
PS-S12	05/25/07	3	3								-					
PS-S16	05/25/07															
RS-S19	5/25/2007	6	6	0-6	100	100	100	99.67	00.12	72.51	16.10	3.86	2.86	2.24	0.59	0.35
RS-S20	05/24/07	12	10	-0	100	100	100	55.01	33.12	12.01	-	5.00	2.00	2.27	0.55	0.55
RS-S21	5/24/2007	9	6	0-6	100	100	100	00.22	98.68	0/ 30	77 21	43.50	14.60	3 30	1.26	0.94
RS-S22	05/24/07	6	6		100	100	100	55.22	30.00		-	40.00	14.00	5.50	1.20	0.34
110 022	00/24/01	0	0	0-6	100	100	100	99.81	99.81	98.69	81 99	29.72	7.02	2.32	0.63	0 44
RS-S23	5/24/2007	12	11	6-11	100	100	100	100	99.96	98.63	88.69	64.39	48.32	21.02	8.09	5.06
RS-S24	05/24/07	9	9		100	100		100	00.00	-	-	0 1100	10102	21101	0.00	0.00
RS-S25	5/24/2007	4	4	0-4	100	100	97.50	96.38	95.15	94.46	93.94	79.58	24.99	9.09	2.21	1.21
RS-S28	05/24/07	6	6							-	-				1	
RS-S33	05/24/07	5	5							-	-					
RS-S36	5/24/2007	6	5	0-5	100	100	100	99.68	99.62	98.08	89.63	49.64	13.52	3.39	1.14	0.93
RS-XXX	05/24/07	6	6		_				•	-	-		•		· · · · · ·	
RS-YYY	05/25/07	3	3							-	-					

Notes:

1. Samples were collected by ARCADIS BBL, and submitted to Geotechnics, Inc. for particle size analysis.

2. Shaded samples were not analyzed for particle size distribution, but are included here to represent location specific probing thicknesses and sediment core recovery lengths.

3. *Indicates field observations made at the time of collection noted a petroleum odor at this location.

Location ID: Sample ID:	RS-C1 RS-C1	RS-C4 RS-C4	RS-C7 RS-C7	RS-C10 RS-C10	RS-C14 RS-C14	RS-C17 RS-C17	RS-C17 RS-C17
Sample Depth(Inches): Parameter Date Collected:	0-3 05/25/07	0-7 05/25/07	0-5 05/25/07	0-3 05/25/07	0-6	0-6	6-25 05/25/07
PCBs	00/20/01	00/20/01	00/20/01	00/20/01	00/20/01	00/20/01	00/20/01
Aroclor-1221	ND(0.023)	ND(0.024)	ND(0.024) [ND(0.023)]	ND(0.066)	ND(0.024)	ND(0.023)	ND(0.26)
Aroclor-1242	ND(0.023)	ND(0.024)	ND(0.024) [ND(0.023)]	ND(0.066)	ND(0.024)	ND(0.023)	ND(0.26)
Aroclor-1248	0.060 J	0.025 J	ND(0.024) [ND(0.023)]	0.19 J	ND(0.024)	ND(0.023)	1.1 J
Aroclor-1254	0.088	0.039	ND(0.024) [ND(0.023)]	0.54	0.055	0.046	2.3
Aroclor-1260	0.032	0.097	0.061 J [0.036 J]	1.3	0.11	0.11	7.2
Total PCBs	0.18 J	0.161 J	0.061 J [0.036 J]	2.03 J	0.165	0.156	10.6 J
Total Organic Carbon							
TOC - Replicate 1 (%)	0.21	0.35	0.19 [0.21]	0.26	0.23	0.24	0.56
TOC - Replicate 2 (%)	0.18	0.67	0.25 [0.77]	0.22	0.23	0.13	1.30
TOC - Replicate 3 (%)	0.16	0.25	0.27 [0.40]	0.23	0.17	0.19	0.94
TOC - Replicate 4 (%)	NA	0.21	[0.16]	NA	NA	0.12	0.57
TOC - Average (%)	0.18	0.37	0.24 [0.38]	0.24	0.21	0.17	0.85
TOC - % RSD	14	56	18 [72]	11	17	33	43

	Location ID:	RS-C26	RS-C29	RS-C29	RS-C31	RS-C34	RS-C37	RS-C37
	Sample ID:	RS-C26	RS-C29	RS-C29	RS-C31	RS-C34	RS-C37	RS-C37
Sample	Depth(Inches):	0-6	0-6	6-8	0-6	0-6	0-6	6-8
Parameter	Date Collected:	05/24/07	05/24/07	05/24/07	05/24/07	05/24/07	05/24/07	05/24/07
PCBs								
Aroclor-1016		ND(0.028)	ND(0.024)	ND(0.23) [ND(0.093)]	ND(0.023)	ND(0.023)	ND(0.024)	ND(0.024)
Aroclor-1221		ND(0.028)	ND(0.024)	ND(0.23) [ND(0.093)]	ND(0.023)	ND(0.023)	ND(0.024)	ND(0.024)
Aroclor-1232		ND(0.028)	ND(0.024)	ND(0.23) [ND(0.093)]	ND(0.023)	ND(0.023)	ND(0.024)	ND(0.024)
Aroclor-1242		ND(0.028)	ND(0.024)	ND(0.23) [ND(0.093)]	ND(0.023)	ND(0.023)	ND(0.024)	ND(0.024)
Aroclor-1248		0.063 J	ND(0.024)	ND(0.23) [0.43 J]	ND(0.023)	ND(0.023)	ND(0.024)	ND(0.024)
Aroclor-1254		0.098	0.024	ND(0.23) [0.49]	0.026	0.094	ND(0.024)	ND(0.024)
Aroclor-1260		0.16	0.091	4.6 J [2.5 J]	0.045	0.064	0.038	0.033
Total PCBs		0.321 J	0.115	4.6 J [3.42 J]	0.071	0.158	0.038	0.033
Total Organic Carbon								
TOC - Replicate 1 (%)		0.53	0.45	1.40 [2.70]	0.13	0.31	0.36	0.81
TOC - Replicate 2 (%)		0.48	0.30	1.30 [3.70]	0.37	0.27	0.52	0.48
TOC - Replicate 3 (%)		0.36	0.26	2.10 [2.40]	0.16	0.23	0.28	0.62
TOC - Replicate 4 (%)		NA	0.42	1.80	0.15	NA	0.17	0.50
TOC - Average (%)		0.46 J	0.36	1.63 J [2.95 J]	0.20	0.27	0.33 J	0.60
TOC - % RSD		20	25	23 [24]	57	15	45	25

	Location ID:	RS-N2	RS-N5	RS-N8	RS-N11	RS-N11	RS-N12	RS-N15
	Sample ID:	RS-N2	RS-N5	RS-N8	RS-N11	RS-N11	RS-N12	RS-N15
Sa	mple Depth(Inches):	0-3	0-6	0-2	0-6	6-10	0-5	0-6
Parameter	Date Collected:	39,227	39,227	39,227	39,227	39,227	05/25/07	05/25/07
PCBs								
Aroclor-1016		ND(0.023)	ND(0.024)	ND(0.022)	ND(0.023)	ND(0.095)	ND(0.024)	ND(0.024)
Aroclor-1221		ND(0.023)	ND(0.024)	ND(0.022)	ND(0.023)	ND(0.095)	ND(0.024)	ND(0.024)
Aroclor-1232		ND(0.023)	ND(0.024)	ND(0.022)	ND(0.023)	ND(0.095)	ND(0.024)	ND(0.024)
Aroclor-1242		ND(0.023)	ND(0.024)	ND(0.022)	ND(0.023)	ND(0.095)	ND(0.024)	ND(0.024)
Aroclor-1248		0.045 J	ND(0.024)	0.023 J	ND(0.023)	ND(0.095)	0.20 J	0.025 J
Aroclor-1254		0.033	0.033	0.25	0.069	1	0.59	0.064
Aroclor-1260		0.051	0.095	0.17	0.19	1.9	0.32	0.085
Total PCBs		0.129 J	0.128	0.443 J	0.259	2.9	1.11 J	0.174 J
Total Organic Carbon								
TOC - Replicate 1 (%)		0.30	0.15	0.24	0.13	0.38	0.20	0.20
TOC - Replicate 2 (%)		0.64	0.17	0.23	1.20	1.20	0.30	3.30
TOC - Replicate 3 (%)		0.40	0.20	0.77	0.45	0.25	0.20	0.21
TOC - Replicate 4 (%)		0.63	NA	0.45	NA	0.25	NA	0.15
TOC - Average (%)		0.49	0.18	0.42	0.55	0.51	0.23	0.97
TOC - % RSD		35	13	60	80	86	24	160
			•		-	•		
	Location ID:	RS-N15	RS-N18	RS-N18	RS-N27	RS-N30	RS-N32	RS-N32
	Sample ID:	RS-N15	RS-N18	RS-N18	RS-N27	RS-N30	RS-N32	RS-N32
Sa	mple Depth(Inches):	6-9	0-6	6-14	0-6	0-4	0-6	6-9
Parameter	Date Collected:	39,227	39,226	39,226	39,226	39,226	05/24/07	05/24/07
PCBs								
Aroclor-1016		ND(0.024)	ND(0.025)	ND(0.024)	ND(0.022)	ND(0.023)	ND(0.022)	ND(0.025)
Aroclor-1221		ND(0.024)	ND(0.025)	ND(0.024)	ND(0.022)	ND(0.023)	ND(0.022)	ND(0.025)
Aroclor-1232		ND(0.024)	ND(0.025)	ND(0.024)	ND(0.022)	ND(0.023)	ND(0.022)	ND(0.025)
Aroclor-1242		ND(0.024)	ND(0.025)	ND(0.024)	ND(0.022)	ND(0.023)	ND(0.022)	ND(0.025)
Aroclor-1248		0.35 J	0.078 J	0.11 J	ND(0.022)	0.025 J	ND(0.022)	0.039 J
Aroclor-1254		0.96	0.18	0.048	ND(0.022)	0.1	ND(0.022)	0.046
Aroclor-1260		0.2	0.11	0.068	0.034	0.04	ND(0.022)	0.14
Total PCBs		1.51 J	0.368 J	0.226 J	0.034	0.165 J	ND(0.022)	0.225 J
Total Organic Carbon								
TOC - Replicate 1 (%)		0.20	0.26	0.14	0.19	1.60	0.15	0.26
TOC - Replicate 2 (%)		0.22	0.51	0.26	0.14	0.29	0.17	0.25
TOC - Replicate 3 (%)		0.20	0.34	0.17	0.13	0.43	0.21	0.22
TOC - Replicate 4 (%)		NA	0.20	0.16	NA	0.25	NA	NA
TOC - Average (%)		0.21	0.33	0.18	0.15	0.65	0.17	0.24
TOC - % RSD		4	41	28	21	100	17	8

Locatio	n ID: RS-N35	RS-N35	RS-S3	RS-S6	RS-S9	RS-S13	RS-S16
Sampl	e ID: RS-N35	RS-N35	RS-S3	RS-S6	RS-S9	RS-S13	RS-S16
Sample Depth(Incl	nes): 0-6	6-8	0-6	0-3	0-3	0-3	0-6
Parameter Date Collect	cted: 39,226	39,226	39,227	39,227	39,227	05/25/07	05/25/07
PCBs							
Aroclor-1016	ND(0.023)	ND(0.023)	ND(0.022)	ND(0.021)	ND(0.024)	ND(0.025)	ND(0.025)
Aroclor-1221	ND(0.023)	ND(0.023)	ND(0.022)	ND(0.021)	ND(0.024)	ND(0.025)	ND(0.025)
Aroclor-1232	ND(0.023)	ND(0.023)	ND(0.022)	ND(0.021)	ND(0.024)	ND(0.025)	ND(0.025)
Aroclor-1242	ND(0.023)	ND(0.023)	0.042 J	ND(0.021)	ND(0.024)	ND(0.025)	ND(0.025)
Aroclor-1248	ND(0.023)	0.039 J	ND(0.022)	ND(0.021)	ND(0.024)	ND(0.025)	ND(0.025)
Aroclor-1254	ND(0.023)	0.073	0.044	0.058	ND(0.024)	0.049	0.047
Aroclor-1260	0.044	0.12	0.034	0.24	ND(0.024)	0.074	0.094
Total PCBs	0.044	0.232 J	0.12 J	0.298	ND(0.024)	0.123	0.141
Total Organic Carbon							
TOC - Replicate 1 (%)	0.16	0.35	0.33	0.24	0.15	0.19	0.15
TOC - Replicate 2 (%)	0.13	0.26	0.19	0.31	0.17	0.39	0.19
TOC - Replicate 3 (%)	0.24	0.25	0.13	0.26	0.12	0.11	0.15
TOC - Replicate 4 (%)	0.27	NA	0.14	NA	NA	0.17	NA
TOC - Average (%)	0.20	0.29	0.20	0.27	0.14	0.22	0.17 J
TOC - % RSD	32	20	47	14	17	58	15
		-	-	-	-		
Locatio	n ID: RS-S16	RS-S19	RS-S20	RS-S20	RS-S21	RS-S22	RS-S23
Sampl	e ID: RS-S16	RS-S19	RS-S20	RS-S20	RS-S21	RS-S22	RS-S23
Sample Depth(Inc	hes): 6-11	0-6	0-6	6-10	0-6	0-6	0-6
Parameter Date Collect	cted: 39,227	39,227	39,226	39,226	39,226	05/24/07	05/24/07
PCBs							
Aroclor-1016	ND(0.027)	ND(0.020)	ND(0.022)	ND(0.022)	ND(0.025)	ND(0.024) [ND(0.024)]	ND(0.023)
Aroclor-1221	ND(0.027)	ND(0.020)	ND(0.022)	ND(0.022)	ND(0.025)	ND(0.024) [0.051 J]	ND(0.023)
Aroclor-1232	ND(0.027)	ND(0.020)	ND(0.022)	ND(0.022)	ND(0.025)	ND(0.024) [ND(0.024)]	ND(0.023)
Aroclor-1242	ND(0.027)	0.12 J	ND(0.022)	ND(0.022)	ND(0.025)	ND(0.024) [ND(0.024)]	ND(0.023)
Aroclor-1248	0.17 J	ND(0.020)	ND(0.022)	ND(0.022)	ND(0.025)	ND(0.024) [0.025 J]	0.024 J
Aroclor-1254	0.2	0.076	ND(0.022)	0.026	0.044	0.047 [0.06]	0.11
Aroclor-1260	0.35	0.048	ND(0.022)	0.024	0.08	0.13 J [0.047 J]	0.028
Total PCBs	0.72 J	0.244 J	ND(0.022)	0.050	0.124	0.177 J [0.183 J]	0.162 J
Total Organic Carbon							
TOC - Replicate 1 (%)	0.87	0.09	0.39	0.41	0.36	0.30 [0.750]	0.16
TOC - Replicate 2 (%)	1.10	0.10	0.14	0.12	0.79	0.31 [0.72]	0.12
TOC - Replicate 3 (%)	0.90	2.40	0.21	0.11	0.20	0.39 [1.30]	0.10
TOC - Replicate 4 (%)	NA	0.21	3.00	0.13	0.20	[0.53]	NA
TOC - Average (%)	0.96	0.70	0.94	0.19	0.39	0.33 J [0.81 J]	0.13
TOC - % RSD	14	160	150	76	72	15 [38]	21

Location ID:	RS-S23	RS-S24	RS-S24	RS-S25	RS-S28	RS-S33	RS-S36
Sample ID:	RS-S23	RS-S24	RS-S24	RS-S25	RS-S28	RS-S33	RS-S36
Sample Depth(Inches):	6-11	0-6	6-9	0-4	0-6	0-5	0-5
Parameter Date Collected:	39,226	39,226	39,226	39,226	39,226	05/24/07	05/24/07
PCBs							
Aroclor-1016	ND(0.024)	ND(0.026)	ND(0.022)	ND(0.025)	ND(0.025)	ND(0.024)	ND(0.024)
Aroclor-1221	ND(0.024)	ND(0.026)	ND(0.022)	ND(0.025)	ND(0.025)	ND(0.024)	ND(0.024)
Aroclor-1232	ND(0.024)	ND(0.026)	ND(0.022)	ND(0.025)	ND(0.025)	ND(0.024)	ND(0.024)
Aroclor-1242	ND(0.024)	ND(0.026)	ND(0.022)	ND(0.025)	ND(0.025)	ND(0.024)	ND(0.024)
Aroclor-1248	0.047 J	ND(0.026)	0.062 J	0.040 J	0.030 J	ND(0.024)	0.076 J
Aroclor-1254	0.073	ND(0.026)	0.27	0.054	0.047	0.056	0.18
Aroclor-1260	0.083	0.052	0.11	0.2	0.073	0.032	0.11
Total PCBs	0.203 J	0.052	0.442 J	0.294 J	0.15 J	0.088	0.366 J
Total Organic Carbon							
TOC - Replicate 1 (%)	0.43	0.22	0.17	0.15	0.81	0.35	0.16
TOC - Replicate 2 (%)	0.44	0.40	0.11	0.18	0.32	0.29	0.14
TOC - Replicate 3 (%)	0.37	0.25	0.15	0.55	0.38	0.23	0.20
TOC - Replicate 4 (%)	NA	1.10	NA	0.12	0.39	NA	NA
TOC - Average (%)	0.41	0.49	0.14	0.25	0.47	0.29	0.17
TOC - % RSD	8	84	22	80	48	21	17

	Location ID:	RS-XXX	RS-YYY
	Sample ID:	RS-XXX	RS-YYY
	Sample Depth(Inches):	0-6	0-3
Parameter	Date Collected:	39,226	39,227
PCBs			
Aroclor-1016		ND(0.023)	ND(0.023)
Aroclor-1221		ND(0.023)	ND(0.023)
Aroclor-1232		ND(0.023)	ND(0.023)
Aroclor-1242		ND(0.023)	ND(0.023)
Aroclor-1248		0.044 J	0.066 J
Aroclor-1254		0.11	0.14
Aroclor-1260		0.16	0.26
Total PCBs		0.314 J	0.466 J
Total Organic Carbon			
TOC - Replicate 1 (%)		0.26	0.33
TOC - Replicate 2 (%)		0.13	0.17
TOC - Replicate 3 (%)		0.23	0.31
TOC - Replicate 4 (%)		0.13	0.26
TOC - Average (%)		0.19	0.26
TOC - % RSD		36	27

UPPER 1/2-MILE REACH OF THE HOUSATONIC RIVER GENERAL ELECTRIC COMPANY - PITTSFIELD, MASSACHUSETTS (Results for PCBs are presented in dry weight mg/kg and results for TOC are presented in percent TOC)

Notes:

- 1. Samples were collected by ARCADIS BBL, and submitted to Northeast Analytical, Inc. for analysis of PCBs and TOC.
- 2. Samples have been validated as per Field Sampling Plan/Quality Assurance Project Plan (FSP/QAPP), General Electric Company, Pittsfield, Massachusetts, ARCADIS BBL (approved June 13, 2007).
- 3. NA Not Analyzed TOC Replicate 4 was analyzed and reported by the laboratory only if the percent relative standard deviation (% RSD) of Replicate 1 through Replicate 3 was creater than 25%. 4. Field duplicate sample results are presented in brackets.

Data Qualifiers:

J - Indicates that the associated numerical value is an estimated concentration.

UPPER 1/2 MILE REACH OF THE HOUSATONIC RIVER GENERAL ELECTRIC COMPANY - PITTSFIELD, MASSACHUSETTS (Results are presented in dry weight mg/kg)

Sam Parameter	Location ID: Sample ID: ple Depth(Inches): Date Collected:	RS-C7 RS-C7 ¹ 0-5 05/25/07	RS-C7 H1-SE001576-0-0000 ² 0-5 05/25/07	RS-C14 RS-C14 ¹ 0-6 05/25/07	RS-C14 H1-SE001573-0-0000 ² 0-6 05/25/07	RS-C17 RS-C17 ¹ 6-25 05/25/07	RS-C17 H1-SE001572-0 / [1]-0005 ² 6-25 05/25/07
PCBs							
Aroclor-1221		ND(0.024) [ND(0.023)]	ND(0.019)	ND(0.024)	ND(0.021)	ND(0.26)	ND(0.25) [ND(0.24)]
Aroclor-1232		ND(0.024) [ND(0.023)]	ND(0.019)	ND(0.024)	ND(0.019)	ND(0.26)	ND(0.24) [ND(0.021)]
Aroclor-1242		ND(0.024) [ND(0.023)]	ND(0.019)	ND(0.024)	ND(0.021)	ND(0.26)	ND(0.25) [ND(0.24)]
Aroclor-1248		ND(0.024) [ND(0.023)]	ND(0.019)	ND(0.024)	ND(0.021)	1.1 J	ND(0.25) [ND(0.24)]
Aroclor-1254		ND(0.024) [ND(0.023)]	0.026	0.055	0.066	2.3	1.4 [1.1]
Aroclor-1260		0.061 J [0.036 J]	0.064	0.11	0.073	7.2	1.6 [2.4]
Total PCBs		0.061 J [0.036 J]	0.090	0.165	0.14	10.6 J	3.0 [3.5]

UPPER 1/2 MILE REACH OF THE HOUSATONIC RIVER GENERAL ELECTRIC COMPANY - PITTSFIELD, MASSACHUSETTS (Results are presented in dry weight mg/kg)

Location ID: Sample ID: Sample Depth(Inches): Parameter Date Collected:	RS-C34 RS-C34 ¹ 0-6 05/24/07	RS-C33 -SE001567-0-000 0-6 05/24/07	RS-C37 RS-C37 ¹ 0-6 05/24/07	RS-C37 H1-SE001566-0-0000 ² 0-6 05/24/07	RS-N5 RS-N5 ¹ 0-6 05/25/07	RS-N5 H1-SE001577-0-0000 ² 0-6 05/25/07
PCBs						
Aroclor-1221	ND(0.023)	ND(0.020)	ND(0.024)	ND(0.021)	ND(0.024)	ND(0.021)
Aroclor-1232	ND(0.023)	ND(0.020)	ND(0.024)	ND(0.021)	ND(0.024)	ND(0.021)
Aroclor-1242	ND(0.023)	ND(0.020)	ND(0.024)	ND(0.021)	ND(0.024)	ND(0.021)
Aroclor-1248	ND(0.023)	ND(0.020)	ND(0.024)	ND(0.021)	ND(0.024)	ND(0.021)
Aroclor-1254	0.094	0.17	ND(0.024)	0.051	0.033	0.091
Aroclor-1260	0.064	0.071	0.033	0.14	0.095	0.16
Total PCBs	0.158	0.241	0.033	0.191	0.128	0.251

UPPER 1/2 MILE REACH OF THE HOUSATONIC RIVER GENERAL ELECTRIC COMPANY - PITTSFIELD, MASSACHUSETTS (Results are presented in dry weight mg/kg)

Location ID: Sample ID: Sample Depth(Inches): Parameter Date Collected:	RS-N11 RS-N11 ¹ 6-10 05/25/07	RS-N11 H1-SE001574-0-0005 ² 6-10 05/25/07	RS-N27 RS-N27 ¹ 0-6 05/24/07	RS-N27 -SE001569-0-00 0-6 05/24/07	RS-N30 RS-N30 ¹ 0-4 05/24/07	RS-N30 H1-SE001568-0-0000 ² 0-4 05/24/07	RS-S9 RS-S9 ¹ 0-3 05/25/07	RS-S9 H1-SE001575-0-0000 ² 0-3 05/25/07
PCBs								
Aroclor-1221	ND(0.095)	ND(0.063)	ND(0.022)	ND(0.037)	ND(0.023)	ND(0.020)	ND(0.024)	ND(0.021)
Aroclor-1232	ND(0.095)	ND(0.063)	ND(0.022)	ND(0.037)	ND(0.023)	ND(0.020)	ND(0.024)	ND(0.021)
Aroclor-1242	ND(0.095)	ND(0.063)	ND(0.022)	ND(0.037)	ND(0.023)	ND(0.020)	ND(0.024)	ND(0.021)
Aroclor-1248	ND(0.095)	ND(0.063)	ND(0.022)	ND(0.037)	0.025 J	ND(0.020)	ND(0.024)	ND(0.021)
Aroclor-1254	1	0.38	ND(0.022)	ND(0.037)	0.1	0.035	ND(0.024)	ND(0.021)
Aroclor-1260	1.9	0.17	0.034	0.24	0.04	0.14	ND(0.024)	0.040
Total PCBs	2.9	0.55	0.034	0.24	0.165 J	0.175	ND(0.024)	0.040

UPPER 1/2 MILE REACH OF THE HOUSATONIC RIVER GENERAL ELECTRIC COMPANY - PITTSFIELD, MASSACHUSETTS (Results are presented in dry weight mg/kg)

Location ID: Sample ID: Depth(Inches): Parameter Date Collected:	RS-S21 RS-S21 ¹ 0-6 05/24/07	RS-S21 H1-SE001571-0-0000 ² 0-6 05/24/07	RS-S24 RS-S24 ¹ 0-6 05/24/07	RS-S24 H1-SE001570-0-0000 ² 0-6 05/24/07
PCBs				
Aroclor-1221	ND(0.025)	ND(0.022)	ND(0.026)	ND(0.042)
Aroclor-1232	ND(0.025)	ND(0.022)	ND(0.026)	ND(0.042)
Aroclor-1242	ND(0.025)	ND(0.022)	ND(0.026)	ND(0.042)
Aroclor-1248	ND(0.025)	ND(0.022)	ND(0.026)	ND(0.042)
Aroclor-1254	0.044	0.050	ND(0.026)	0.069
Aroclor-1260	0.08	0.038	0.052	0.29
Total PCBs	0.124	0.088	0.052	0.359

Notes:

1. GE Samples were collected by ARCADIS BBL, and submitted to Northeast Analytical, Inc. for analysis of PCBs and TOC.

2. EPA split samples were collected by Weston Solutions, Inc.

 GE analytical data have been validated as per Field Sampling Plan/Quality Assurance Project Plan (FSP/QAPP), General Electric Company, Pittsfield, Massachusetts, ARCADIS BBL (approved June 13, 2007).

4. Field duplicate SAMPLE ANALYTICAL RESULTS are presented in brackets.

5. Sample pairs are alternately shaded and unshaded.

Data Qualifiers:

J - Indicates that the associated numerical value is an estimated concentration.

TABLE 4 SUMMARY OF RECENT AND PRIOR ISOLATION LAYER PCB & TOC ANALYTICAL RESULTS

UPPER 1/2-MILE REACH OF THE HOUSATONIC RIVER GENERAL ELECTRIC COMPANY - PITTSFIELD, MASSACHUSETTS

		P	ost Excavati	ion Sediment F	Results	Depth	1	Isolation Layer - Baselin	e		Isolation Layer - 1-Yea	r	Isolation Layer - 5-Year			
Cell	Sample ID	Date	Depth Interval	Total PCB (mg/kg)	AVG TOC (%)	Interval	Sample Date	Total PCB (mg/kg)	AVG TOC (%)	Sample Date	Total PCB (mg/kg)	AVG TOC (%)	Sample Date	Total PCB (mg/kg)	AVG TOC (%)	
						2" - 4"	11/9/00	0.027J	Rejected	11/5/01	ND(0.0551)	0.10	8/10/07	0.064	0.55	
G1	CAP-MON -1	6/23/00	Surface	20	0.45	4" - 6"	11/9/00	ND(0.038)	Rejected	11/5/01	0.0790	0.15	8/10/07	ND(0.055)	0.45	
						6" - 8"	11/9/00	ND(0.040)	Rejected	11/5/01	ND(0.0576)	0.14	8/10/07	ND(0.056)	0.34	
						2" - 4"	11/9/00	ND(0.039)	Rejected	11/5/01	0.0845[0.074]	0.15 [0.10]	8/10/07	0.076	0.75	
G1	CAP-MON -2	8/17/00	Surface	19.0	ND(0.60)	4" - 6"	11/9/00	ND(0.040)	Rejected	11/5/01	ND(0.0581)	0.09	8/10/07	ND(0.057)	0.49	
						6" - 8"	11/9/00	ND(0.039)	Rejected	11/5/01	ND(0.0588)	0.08	8/10/07	ND(0.056)	0.43	
						2" - 4"	11/9/00	ND(0.039)	Rejected	11/5/01	ND(0.0570)	0.07	8/10/07	ND(0.057)	0.46	
G2	CAP-MON -3	8/17/00	Surface	1.72	ND(0.12)	4" - 6"	11/9/00	0.030J	Rejected	11/5/01	ND(0.0552)	0.09	8/10/07	ND(0.056)	0.21	
					6" - 8"	11/9/00	ND(0.039)	Rejected	11/5/01	ND(0.0575)	0.11	8/10/07	0.07	0.38		
					2" - 4"	2/27/01	ND(0.0636)	Rejected	2/27/02	ND(0.0570)	0.46	8/10/07	ND(0.058)	1.2		
G3	CAP-MON -4	2/22/01	Surface	519	NS	4" - 6"	2/27/01	ND(0.0580)	Rejected	2/27/02	ND(0.0569)	0.36	8/10/07	ND(0.058)	1.4	
						6" - 8"	2/27/01	ND(0.0558)	Rejected	2/27/02	ND(0.0553)	0.36 [0.35]	8/10/07	ND(0.057)	1.2	
						2" - 4"	5/10/01	ND(0.0582)	Rejected	7/3/02	ND(0.0588)	0.63 [0.50]	8/10/07	ND(0.057)	1.8	
F3	CAP-MON -5	5/4/01	Surface	8.46	NS	4" - 6"	5/10/2001	ND(0.0559)	Rejected	7/3/2002	ND(0.0589)	0.46	8/10/07	ND(0.059)	1.2	
						6" - 8"	5/10/2001	ND(0.0583)	Rejected	7/3/2002	ND(0.0591)	0.51	8/10/07	ND(0.058)	1.1	
						2" - 4"	1/30/02	ND(0.061) [ND(0.0586)]	0.87 [0.91]	8/27/03	ND(0.061)	1.00	8/10/07	0.21	1.2	
J1	CAP-MON -6	1/15/02	Surface	1,000	NS	4" - 6"	1/30/02	ND(0.061) [ND(0.0586)]	1.22	8/27/03	ND(0.059	1.30	8/10/07	ND(0.060)	1.7	
						6" - 8"	1/30/02	ND(0.061) [ND(0.0586)]	1.50 [1.10]	8/27/03	ND(0.061) [ND(0.060)]	1.50 [1.10]	8/10/07	ND(0.060)	1.8	
						2" - 4"	8/16/02	ND(0.054) [ND(0.053)]	1.0 [0.89]	8/27/03	ND(0.058)	1.10	8/10/07	ND(0.059)	1.5	
J3	CAP-MON -7	8/2/02	Surface	88.8	NS	4" - 6"	8/16/02	ND(0.055)	1.10	8/27/03	ND(0.058)	1.10	8/10/07	ND(0.058)	1.1	
						6" - 8"	8/16/02	ND(0.058)	0.67	8/27/03	ND(0.060)	1.20	8/10/07	ND(0.057)	1.2	
						2" - 4"	8/16/02	ND(0.057)	0.91	8/27/03	ND(0.060)	1.10	8/10/07	0.16	0.78	
J3	CAP-MON -8	8/2/02	Surface	216	NS	4" - 6"	8/16/02	ND(0.052)	0.62	8/27/03	ND(0.058)	0.88	8/10/07	0.11	1.1	
						6" - 8"	8/16/02	ND(0.054)	0.73	8/27/03	0.062	0.97	8/10/07	ND(0.055)	1.1	

Notes: 1. TOC = Total Organic Carbon

NA = Not Applicable

ND - Analyte was not detected. The value in parentheses is the associated detection limit.

J - Indicates an estimated value less than the practical quantitation limit (PQL).

2. Duplicate sample results presented in brackets.

3. Depth intervals were measured upward from the geotextile liner at the sediment/isolation layer interface in 2-inch increments.





	LEGEND:
	APPROXIMATE WATER LINE
	BUILDING
* * * *	CHAIN LINK FENCE
$\sim\sim\sim$	TREE/SHRUB
A	2007 DEPOSITED SEDIMENT SAMPLING LOCATION
0	2007 ISOLATION LAYER SAMPLE COLLECTION LOCATION
	REMOVAL CELL BOUNDARY
	REMOVAL AREAS INCLUDED IN THE 1/2-MILE REACH REMOVAL ACTION

NOTES:

1. ALL LOCATIONS AND SURFACE FEATURES ARE APPROXIMATE.

GRAPHIC SCALE

GENERAL ELECTRIC COMPANY PITTSFIELD, MASSACHUSETTS UPPER 1/2-MILE REACH OF THE HOUSATONIC RIVER

2007 SEDIMENT AND ISOLATION LAYER SAMPLING LOCATIONS

